



N-Channel NexFET™ Power MOSFETs

Check for Samples: CSD16325Q5

FEATURES

- · Optimized for 5V Gate Drive
- Ultralow Q_q and Q_{qd}
- Low Thermal Resistance
- Avalanche Rated
- Pb Free Terminal Plating
- RoHS Compliant
- Halogen Free
- SON 5-mm × 6-mm Plastic Package

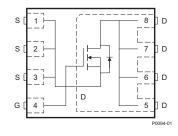
APPLICATIONS

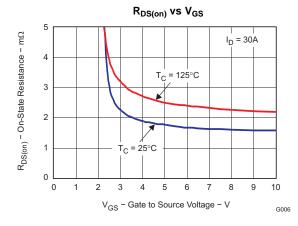
- Point-of-Load Synchronous Buck in Networking, Telecom and Computing Systems
- Optimized for Synchronous FET Applications

DESCRIPTION

The NexFET™ power MOSFET has been designed to minimize losses in power conversion applications and optimized for 5V gate drive applications.

Top View





PRODUCT SUMMARY

V_{DS}	Drain to Source Voltage	25	٧	
Q_g	Gate Charge Total (4.5V)		nC	
Q_{gd}	Gate Charge Gate to Drain	3.5	nC	
		$V_{GS} = 3V$	2.1	mΩ
R _{DS(on)}	Drain to Source On Resistance	V _{GS} = 4.5V 1.7		mΩ
		V _{GS} = 8V 1.5		mΩ
V _{GS(th)}	Threshold Voltage	1.1	V	

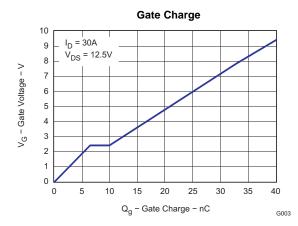
ORDERING INFORMATION

Device	Package	Media	Qty	Ship
CSD16325Q5	SON 5-mm × 6-mm Plastic Package	13-Inch Reel	2500	Tape and Reel

ABSOLUTE MAXIMUM RATINGS

T _A = 2	5°C unless otherwise stated	VALUE	UNIT
V_{DS}	Drain to Source Voltage	25	٧
V_{GS}	Gate to Source Voltage	+10 / -8	V
	Continuous Drain Current, T _C = 25°C	100	Α
I _D	Continuous Drain Current ⁽¹⁾	33	Α
I_{DM}	Pulsed Drain Current, T _A = 25°C ⁽²⁾	200	Α
P_D	Power Dissipation ⁽¹⁾	3.1	W
T_J , T_{STG}	Operating Junction and Storage Temperature Range	-55 to 150	°C
E _{AS}	Avalanche Energy, single pulse $I_D = 100A$, $L = 0.1mH$, $R_G = 25\Omega$	500	mJ

- (1) Typical $R_{\theta JA}=38^{\circ}\text{C/W}$ on 1-inch² (6.45-cm²), 2-oz. (0.071-mm thick) Cu pad on a 0.06-inch (1.52-mm) thick FR4 PCB.
- (2) Pulse duration ≤300µs, duty cycle ≤2%



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NexFET is a trademark of Texas Instruments.





These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

ELECTRICAL CHARACTERISTICS

(T_A = 25°C unless otherwise stated)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Static CI	haracteristics					
BV _{DSS}	Drain to Source Voltage	$V_{GS} = 0V, I_D = 250\mu A$	25			V
I _{DSS}	Drain to Source Leakage Current	V _{GS} = 0V, V _{DS} = 20V			1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{DS} = 0V, V_{GS} = +10/-8V$			100	nA
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	0.9	1.1	1.4	V
		$V_{GS} = 3V, I_{D} = 30A$		2.1	2.9	mΩ
R _{DS(on)}	Drain to Source On Resistance	$V_{GS} = 4.5V, I_D = 30A$		1.7	2.2	mΩ
		$V_{GS} = 8V, I_{D} = 30A$		1.5	2	mΩ
9 _{fs}	Transconductance	$V_{DS} = 15V, I_D = 30A$		159		S
Dynamic	Characteristics	•			•	
C _{iss}	Input Capacitance			3070	4000	pF
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 12.5V,$ $f = 1MHz$		2190	2850	pF
C _{rss}	Reverse Transfer Capacitance	1 - 10112		120	150	pF
R _G	Series Gate Resistance			1.6	3.2	Ω
Qg	Gate Charge Total (4.5V)			18	25	nC
Q _{gd}	Gate Charge – Gate to Drain	$V_{DS} = 12.5V$,		3.5		nC
Q _{gs}	Gate Charge – Gate to Source	I _{DS} = 30A		6.6		nC
Q _{g(th)}	Gate Charge at Vth			3.3		nC
Q _{oss}	Output Charge	V _{DS} = 13V, V _{GS} = 0V		43		nC
t _{d(on)}	Turn On Delay Time			10.5		ns
t _r	Rise Time	V _{DS} = 12.5V, V _{GS} = 4.5V,		16		ns
t _{d(off)}	Turn Off Delay Time	$I_{DS} = 30A$, $R_G = 2\Omega$		32		ns
t _f	Fall Time			12		ns
Diode C	haracteristics	· · · · · · · · · · · · · · · · · · ·				
V _{SD}	Diode Forward Voltage	I _{DS} = 30A, V _{GS} = 0V		0.8	1	V
Q _{rr}	Reverse Recovery Charge	$V_{DD} = 10V$, $I_F = 30A$, $di/dt = 300A/\mu s$		63		nC
t _{rr}	Reverse Recovery Time	$V_{DD} = 10V$, $I_F = 30A$, $di/dt = 300A/\mu s$		47		ns

THERMAL CHARACTERISTICS

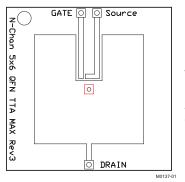
(T_A = 25°C unless otherwise stated)

	PARAMETER	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Thermal Resistance Junction to Case ⁽¹⁾			1	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient ⁽¹⁾ (2)			50	°C/W

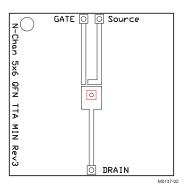
 ⁽¹⁾ R_{θJC} is determined with the device mounted on a 1-inch² (6.45-cm²), 2-oz. (0.071-mm thick) Cu pad on a 1.5-inch × 1.5-inch (3.81-cm × 3.81-cm), 0.06-inch (1.52-mm) thick FR4 PCB. R_{θJC} is specified by design, whereas R_{θJA} is determined by the user's board design.
 (2) Device mounted on FR4 material with 1-inch² (6.45-cm²), 2-oz. (0.071-mm thick) Cu.

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Max $R_{\theta JA} = 50^{\circ} C/W$ when mounted on 1 inch² (6.45 cm²) of 2-oz. (0.071-mm thick) Cu.



Max $R_{\theta JA} = 126^{\circ} C/W$ when mounted on minimum pad area of 2-oz. (0.071-mm thick) Cu.

TYPICAL MOSFET CHARACTERISTICS

 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$

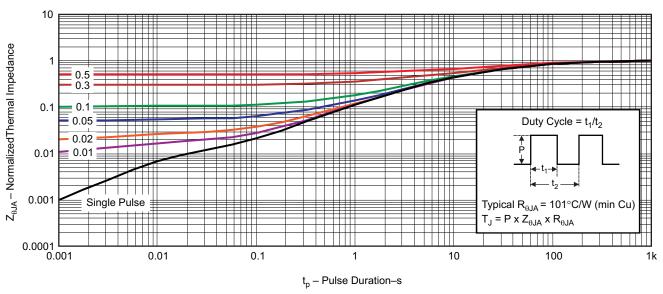


Figure 1. Transient Thermal Impedance

G012



TYPICAL MOSFET CHARACTERISTICS (continued)

$(T_A = 25^{\circ}C \text{ unless otherwise stated})$

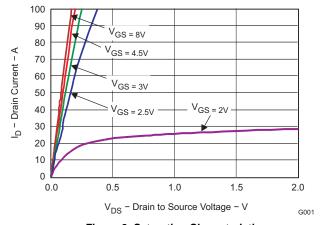


Figure 2. Saturation Characteristics

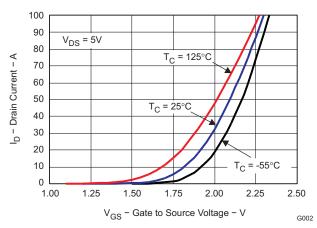


Figure 3. Transfer Characteristics

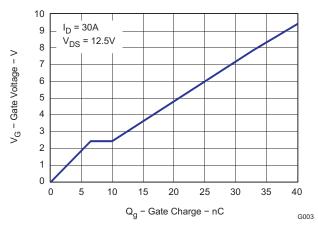


Figure 4. Gate Charge

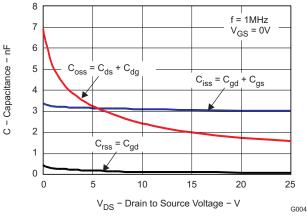


Figure 5. Capacitance

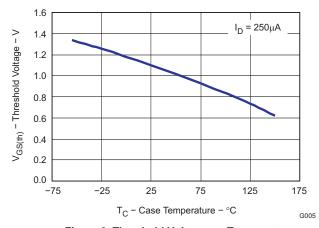


Figure 6. Threshold Voltage vs. Temperature

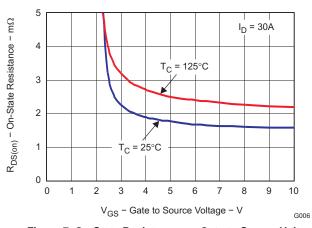


Figure 7. On-State Resistance vs. Gate to Source Voltage



TYPICAL MOSFET CHARACTERISTICS (continued)

$(T_A = 25^{\circ}C \text{ unless otherwise stated})$

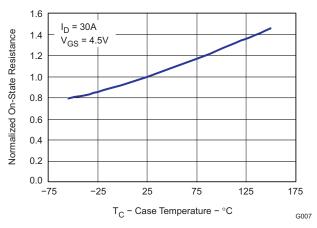


Figure 8. Normalized On-State Resistance vs. Temperature

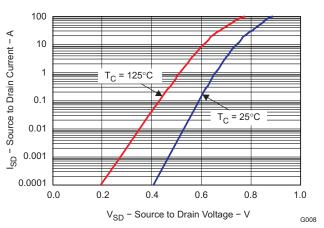


Figure 9. Typical Diode Forward Voltage

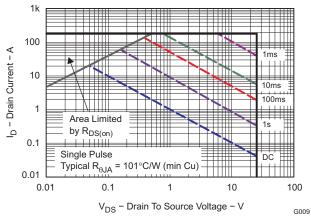


Figure 10. Maximum Safe Operating Area

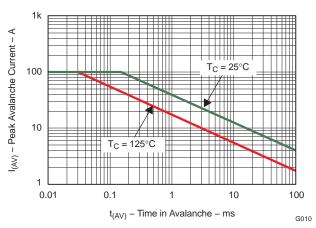


Figure 11. Single Pulse Unclamped Inductive Switching

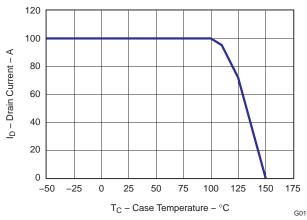
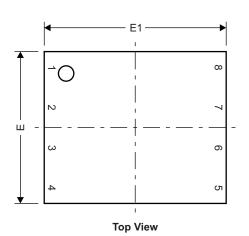


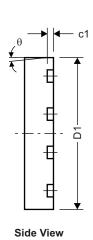
Figure 12. Maximum Drain Current vs. Temperature

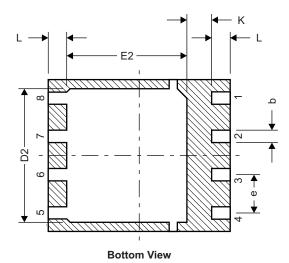


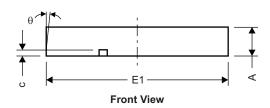
MECHANICAL DATA

Q5 Package Dimensions





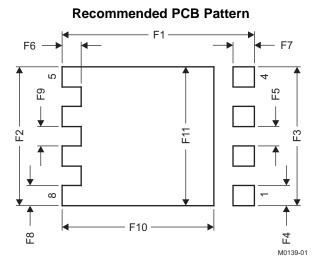




M0140-01

DIM	MILLIN	IETERS	INCI	HES
DIM	MIN	MAX	MIN	MAX
Α	0.950	1.050	0.037	0.039
b	0.360	0.460	0.014	0.018
С	0.150	0.250	0.006	0.010
c1	0.150	0.250	0.006	0.010
D1	4.900 5.100		0.193	0.201
D2	4.320 4.520		0.170	0.178
Е	4.900	5.100	0.193	0.201
E1	5.900	6.100	0.232	0.240
E2	3.920	4.12	0.154	0.162
е	1.27	TYP	0.0	50
L	0.510	0.710	0.020	0.028
θ	0.00			<u>-</u>

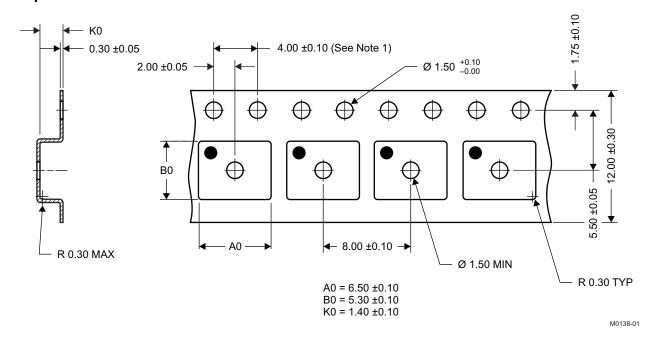




DIM	MILLIN	METERS	INC	HES
DIN	MIN	MAX	MIN	MAX
F1	6.205	6.305	0.244	0.248
F2	4.46	4.56	0.176	0.18
F3	4.46	4.56	0.176	0.18
F4	0.65	0.7	0.026	0.028
F5	0.62	0.67	0.024	0.026
F6	0.63	0.68	0.025	0.027
F7	0.7	0.8	0.028	0.031
F8	0.65	0.7	0.026	0.028
F9	0.62	0.67	0.024	0.026
F10	4.9	5	0.193	0.197
F11	4.46	4.56	0.176	0.18

For recommended circuit layout for PCB designs, see application note SLPA005 – Reducing Ringing Through PCB Layout Techniques.

Q5 Tape and Reel Information



Notes:

- 1. 10-sprocket hole-pitch cumulative tolerance ±0.2
- 2. Camber not to exceed 1mm in 100mm, noncumulative over 250mm
- 3. Material: black static-dissipative polystyrene
- 4. All dimensions are in mm, unless otherwise specified.
- 5. A0 and B0 measured on a plane 0.3mm above the bottom of the pocket
- 6. MSL1 260°C (IR and convection) PbF reflow compatible



REVISION HISTORY

Changes from Original (August 2009) to Revision A	Page
Changed Q _{rr} Reverse Recovery Charge typical value From: 102nC To: 63nC	2
Changes from Revision A (September 2009) to Revision B	Page
• Changed Note 1 of the ABSOLUTE MAXIMUM RATINGS From: $R_{\theta JA} = 38^{\circ}\text{C/W}$ To: Typical $R_{\theta JA} = 38^{\circ}\text{C/W}$	1
 Changed I_{DM} Pulsed Drain Current in the ABSOLUTE MAXIMUM RATINGS From: 210A To: 200A 	1
 Changed From: Max R_{θJA} = 48°C/W To: Max R_{θJA} = 50°C/W 	3
• Changed From: Max R _{θJA} = 113°C/W To: Max R _{θJA} = 126°C/W	3
• Changed Figure 1 text - From: R _{θJA} = 101°C/W To: Typical R _{θJA} = 101°C/W	
• Changed Figure 10 text - From: R _{θJA} = 101°C/W To: Typical R _{θJA} = 101°C/W	5
Changes from Revision B (April 2010) to Revision C	Page
• Changed R _{DS(on)} - V _{GS} = 3V in the Electrical Characteristics table From: 2.7 to 2.9 in the max column	2
Deleted the Package Marking Information section	7



PACKAGE OPTION ADDENDUM

10-Dec-2020

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CSD16325Q5	ACTIVE	VSON-CLIP	DQH	8	2500	RoHS-Exempt & Green	SN	Level-1-260C-UNLIM	-55 to 150	CSD16325	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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